NOV 0 4 2002 orney Docket No. Patent 81329A

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of: JOSEPH J. DANKO

Serial No: 09/579,593

Group Art Unit: 2877

Filed: May 26, 2000

Examiner: G. J. Stock, Jr.

For: METHOD AND APPARATUS FOR INSPECTING A PATTERNED

SEMICONDUCTOR WAFER

Box Fee Amendment Commissioner for Patents Washington, D. C. 20231

Dear Sir:

REQUEST FOR APPROVAL OF DRAWING CHANGE

It is respectfully requested that the Examiner approve the drawing change to Fig. 5 shown in red in the accompanying sheet. The change involves deleting reference numeral 61.

Respectfully submitted.

Kriegsman

Reg. No. 22,733

KRIEGSMAN & KRIEGSMAN

665 Franklin Street

Framingham, MA 01702

(508) 879-3500

Date: 10-30-02

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to Box Fee Amendment, Commissioner of Patents, Washington, D. C. 20231 on 10-30-02

